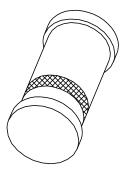
#### DISCRETE SEMICONDUCTORS

# DATA SHEET



## BAS32L High-speed diode

Product specification Supersedes data of November 1993 File under Discrete Semiconductors, SC01 1996 Apr 23





## **High-speed diode**

BAS32L

#### **FEATURES**

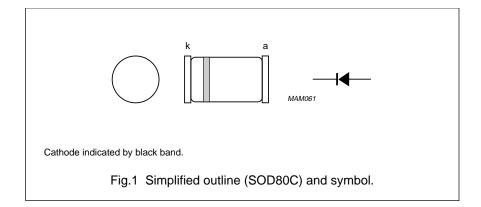
- Small hermetically sealed glass SMD package
- High switching speed: max. 4 ns
- Continuous reverse voltage: max. 75 V
- Repetitive peak reverse voltage: max. 75 V
- Repetitive peak forward current: max. 450 mA
- Forward voltage: max. 1 V.

#### **APPLICATIONS**

- · High-speed switching
- Fast logic applications.

#### **DESCRIPTION**

The BAS32L is a high-speed switching diode fabricated in planar technology, and encapsulated in the small hermetically sealed glass SOD80C SMD package.



#### **LIMITING VALUES**

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>RRM</sub>	repetitive peak reverse voltage		_	75	V
$V_R$	continuous reverse voltage		_	75	V
I <sub>F</sub>	continuous forward current	see Fig.2; note 1	_	200	mA
I <sub>FRM</sub>	repetitive peak forward current		_	450	mA
I <sub>FSM</sub>	non-repetitive peak forward current	square wave; T <sub>j</sub> = 25 °C prior to surge; see Fig.4			
		t = 1 μs	_	4	A
		t = 1 ms	_	1	A
		t = 1 s	_	0.5	A
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = 25 °C; note 1	_	500	mW
T <sub>stg</sub>	storage temperature		-65	+200	°C
Tj	junction temperature		_	200	°C

#### Note

1. Device mounted on an FR4 printed-circuit board.

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#### **ELECTRICAL CHARACTERISTICS**

 $T_i = 25$  °C; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>F</sub>	forward voltage	see Fig.3			
		$I_F = 5 \text{ mA}$	620	750	mV
		I <sub>F</sub> = 100 mA	_	1000	mV
		I <sub>F</sub> = 100 mA; T <sub>j</sub> = 100 °C	_	930	mV
I <sub>R</sub>	reverse current	see Fig.5			
		V <sub>R</sub> = 20 V	_	25	nA
		V <sub>R</sub> = 75 V	_	5	μΑ
		V <sub>R</sub> = 20 V; T <sub>j</sub> = 150 °C	_	50	μΑ
		V <sub>R</sub> = 75 V; T <sub>j</sub> = 150 °C	_	100	μΑ
$V_{(BR)R}$	reverse breakdown voltage	I <sub>R</sub> = 100 μA	100	_	٧
C <sub>d</sub>	diode capacitance	f = 1 MHz; V <sub>R</sub> = 0; see Fig.6		2	pF
t <sub>rr</sub>	reverse recovery time	when switched from $I_F$ = 10 mA to $I_R$ = 10 mA; $R_L$ = 100 $\Omega$ ; measured at $I_R$ = 1 mA; see Fig.7		4	ns
V <sub>fr</sub>	forward recovery voltage	when switched from $I_F = 50$ mA; $t_r = 20$ ns; see Fig.8	ı	2.5	V

#### THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
R <sub>th j-tp</sub>	thermal resistance from junction to tie-point		300	K/W
R <sub>th j-a</sub>	thermal resistance from junction to ambient	note 1	350	K/W

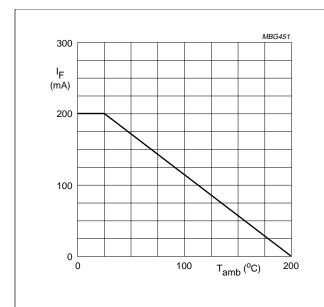
#### Note

1. Device mounted on an FR4 printed-circuit board.

## High-speed diode

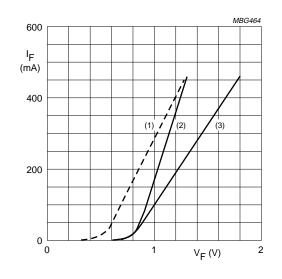
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#### **GRAPHICAL DATA**



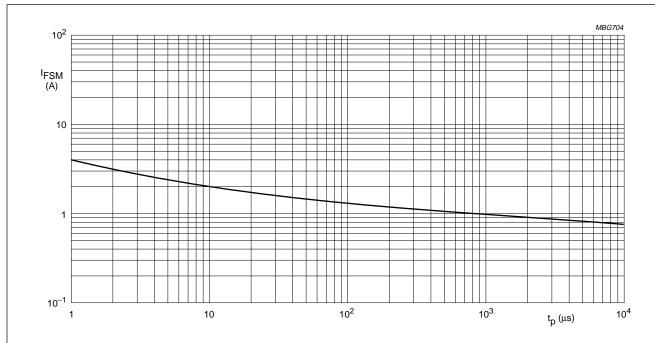
Device mounted on an FR4 printed-circuit board.

Fig.2 Maximum permissible continuous forward current as a function of ambient temperature.



- (1)  $T_j = 175$  °C; typical values.
- (2)  $T_j = 25$  °C; typical values.
- (3)  $T_j = 25$  °C; maximum values.

Fig.3 Forward current as a function of forward voltage.



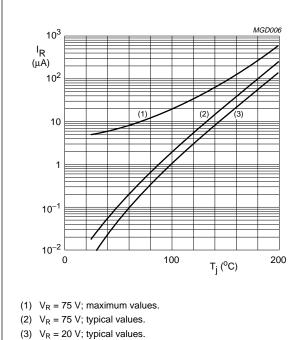
Based on square wave currents.

 $T_j = 25$  °C prior to surge.

Fig.4 Maximum permissible non-repetitive peak forward current as a function of pulse duration.

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Reverse current as a function of junction temperature.

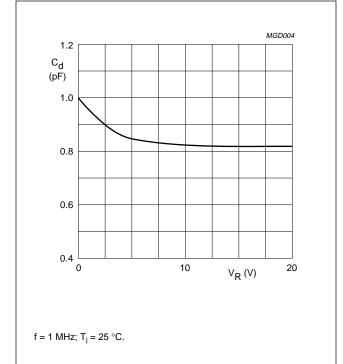


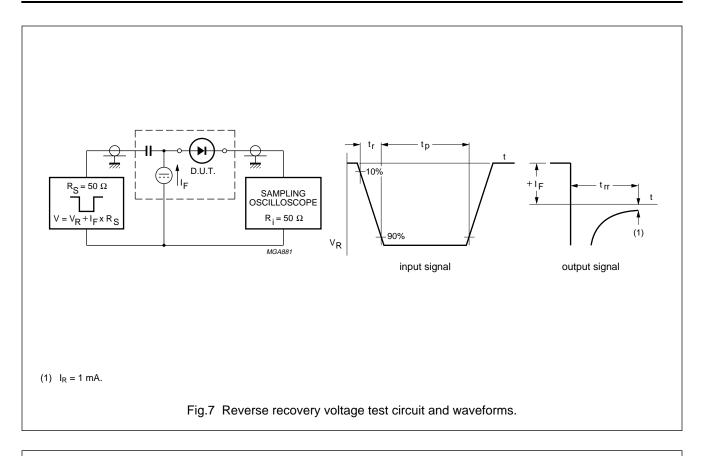
Fig.6 Diode capacitance as a function of reverse voltage; typical values.

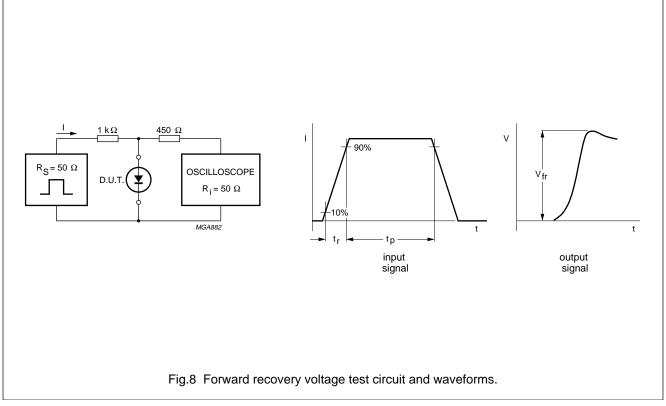
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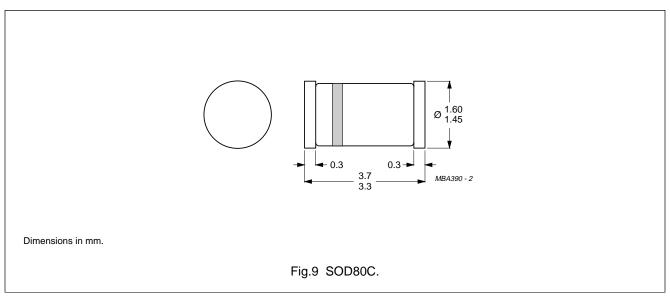




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#### **PACKAGE OUTLINE**



#### **DEFINITIONS**

Data Sheet Status		
Objective specification	This data sheet contains target or goal specifications for product development.	
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.	
Product specification	This data sheet contains final product specifications.	
Limiting values		
Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or		

Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

#### Application information

Where application information is given, it is advisory and does not form part of the specification.

#### LIFE SUPPORT APPLICATIONS

These products are not designed for use in life support appliances, devices, or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips for any damages resulting from such improper use or sale.